

<b>Notice of References Cited</b>	Application/Control No. 09/608,311	Applicant(s)/Patent Under Reexamination XIANG ET AL.	
	Examiner Paresh Patel	Art Unit 2829	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,947,034	08-1990	Wickramasinghe et al.	250/216
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Controlling and tuning strong optical field gradients at a local probe microscope tip apex" by Martin et al. American Institute of Physics [S0003-6951(97)03206-3] 10 Feb. 1997.
	V	"Facts and artifacts in near-field optical microscopy" by Hecht et al. American Institute of Physics [S0021-8979(97)00305-8] 15 March 1997.
	W	"Sub-wavelength patterning of the optical near-field" by Quidant et al. OSA, 26 Jan. 2004/Vol. 12
	X	"Apertureless near-field optical microscope" by Wickramasinghe et al. Applied Physics Letters (ISSN 0003-6951), vol. 65, no. 13, p. 1623-1625, 09/1994.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.